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SYSTEM AND METHOD OF DISTRIBUTED CONTINUOUS CHARACTERIZATION OF AN OPTICAL FIBER MEDIA

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Code

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Application areas

- Information and Communication Technologies
- Industrial Manufacture, Material and Transport technologies
- Energy

Type of Collaboration

- Technical cooperation
- Commercial agreement and Technical assistance
- License agreement

Main Researchers

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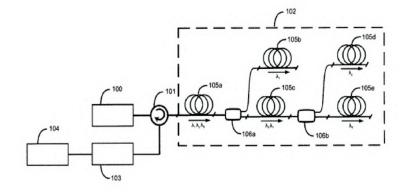
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ABSTRACT

It is a system and a sensing method which allows the fully distributed characterization of optical fiber media with an arbitrary branching of ramifications using wavelength multiplexing techniques to interrogate and identify the different branches of such optical fiber media. As a first aspect of the invention, is presented a distributed characterization system with at least one branch in which there are two or more segments of optical fibers. As a second aspect of the invention, is presented a distributed characterization method applied to an optic fiber media, with at least one branch comprising at least two optical fiber segments.

In one of its preferential implementations, the method consists on characterize the optical fiber media by an optical reflectometry technique sensible to the phase (ϕ OTDR).

ADVANTAGES AND INNOVATIONS

The system and the method of the present invention allow the characterization of optic fiber medias with an arbitrary topology branches without using measurement equip- ment in each ramification.

The competitive advantages of this invention are as follows: Application in complex networks with arbitrary branches without adding measuring equipment in each of the branches. Characterization fully distributed, providing decisive measures in length, continuous, and not sampled. Adaptation to any fiber optic topology, sensing techniques and distributed metrology.